# CT/FCT TEST PROBES

### Spring-loaded test probe GKS-075 291 064 A 1000 LP

Item GKS-075-0799





- Well-established test probes for contacting PCBs
- For optimal contact to the test points (e.g. pads, vias, and pins), various tip styles with various diameters and finishes are available.
- Various spring forces available as well as versions with stainless steel springs suitable for high temperatures
- Used for setting the optimum stroke conditions in the test fixture, various installation heights can be achieved by combining test probes and receptacles

#### **General data**

Product group	ICT / FCT (in-circuit test and function test
Sub-product group	Standard stroke test probe
Series	GKS-075 LP long version
Grid	1.91 mm [75 mil]
Contacting from	Pad, via
Magnetic	Yes
Installation type	Plug-in
Quick-exchange system	Yes
Adjustable installation h	eight No
Non-rotating	No
Compatible receptacle(s	S) KS-075
Min. temperature	- 40 °C [- 104 °F]
Max. temperature	+ 80 °C [+ 176 °F]
RoHS-compliant	RoHS-3;6a



Current load capacity / rated current 3 A
Typical resistance (Ri) <20 mOhm

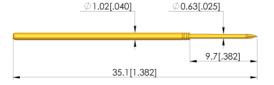
#### **Mechanical data**

Total length	35.1 mm [1.38 in]
Barrel diameter	1.02 mm [.040 in]
Maximum stroke	6.35 mm [.25 in]
Spring pre-load	0.4 N [1.43 ozf]
Collar height	00
Spring force at working stroke	1 N [3.59 ozf]
Recommended working stroke	4.3 mm [.169 in]

#### Tip style data

91 dagger, self-cleaning
0.64 mm [.025 in
A gold
2 stee



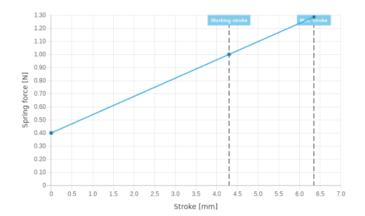




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Learn more about ICT/FCT Test probes

